

FEATURES

- RS-232 Bus-Pin ESD Protection Exceeds ± 15 kV Using Human-Body Model (HBM)
- Meets or Exceeds the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Operates at 5-V V_{CC} Supply
- Four Drivers and Five Receivers
- Operates up to 120 kbit/s
- Low Supply Current in Shutdown Mode . . . 1 μ A Typical
- External Capacitors . . . $4 \times 0.1 \mu$ F
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II

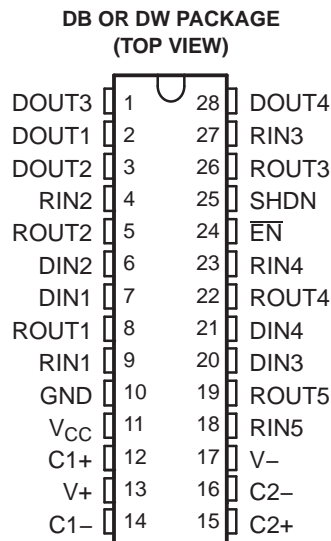
APPLICATIONS

- Battery-Powered Systems
- PDAs
- Notebooks
- Laptops
- Palmtop PCs
- Hand-Held Equipment

DESCRIPTION/ORDERING INFORMATION

The TRS211 device consists of four line drivers, five line receivers, and a dual charge-pump circuit with ± 15 -kV ESD protection pin to pin (serial-port connection pins, including GND). The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 5-V supply. The devices operate at data signaling rates up to 120 kbit/s and a maximum of 30-V/ μ s driver output slew rate.

The TRS211 has both shutdown (SHDN) and enable control (\overline{EN}). In shutdown mode, the charge pumps are turned off, V+ is pulled down to V_{CC} , V– is pulled to GND, and the transmitter outputs are disabled. This reduces supply current typically to 1 μ A. \overline{EN} is used to put the receiver outputs into the high-impedance state to allow wired-OR connection of two RS-232 ports. It has no effect on the RS-232 drivers or the charge pumps.



ORDERING INFORMATION

T_A	PACKAGE ⁽¹⁾⁽²⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING
0°C to 70°C	SOIC – DW	Tube of 20	TRS211CDW	TRS211C
		Reel of 1000	TRS211CDWR	
	SSOP – DB	Tube of 50	TRS211CDB	TRS211C
		Reel of 2000	TRS211CDBR	
–40°C to 85°C	SOIC – DW	Tube of 20	TRS211IDW	TRS211I
		Reel of 1000	TRS211IDWR	
	SSOP – DB	Tube of 50	TRS211IDB	TRS211I
		Reel of 2000	TRS211IDBR	

(1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

(2) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

FUNCTION TABLES⁽¹⁾

INPUTS		DRIVER	RECEIVER	DEVICE STATUS
SHDN	EN			
L	L	All active	All active	Normal operation
L	H	All active	Z	Normal operation
H	X	Z	Z	Shutdown

(1) X = don't care, Z = high impedance

Each Driver⁽¹⁾

INPUTS		OUTPUT DOUT	DRIVER STATUS
DIN	SHDN		
L	L	H	Normal operation
H	L	L	
X	H	Z	Powered off

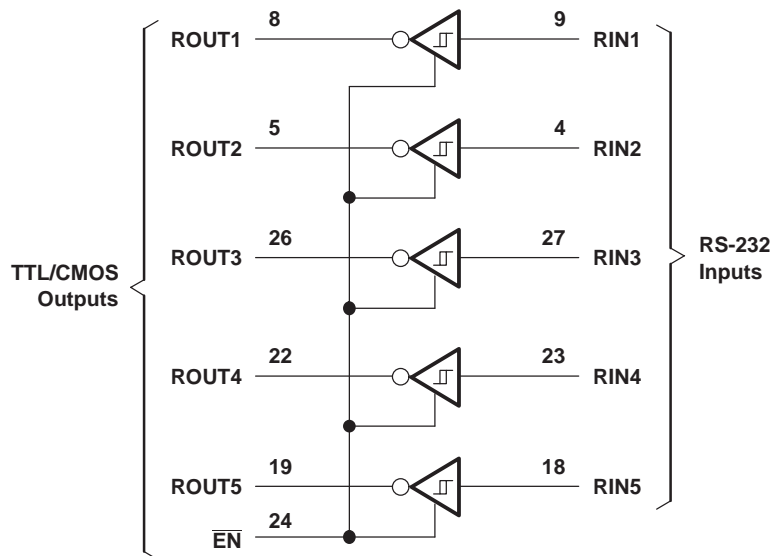
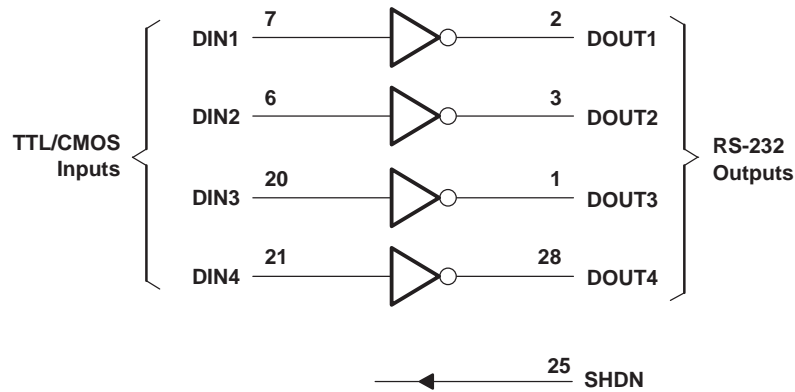
(1) X = don't care, Z = high impedance

Each Receiver⁽¹⁾

INPUTS		OUTPUT ROUT	RECEIVER STATUS
RIN	EN		
L	L	H	Normal operation
H	L	L	
X	H	Z	Powered off

(1) X = don't care, Z = high impedance

LOGIC DIAGRAM (POSITIVE LOGIC)



TRS211

5-V MULTICHANNEL RS-232 LINE DRIVER/RECEIVER WITH ± 15 -kV ESD PROTECTION

SLLS811–JULY 2007

Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_{CC}	Supply voltage range ⁽²⁾	-0.3	6	V
V+	Positive charge pump voltage range ⁽²⁾	$V_{CC} - 0.3$	14	V
V-	Negative charge pump voltage range ⁽²⁾	0.3	-14	V
V_I	Input voltage range	Drivers	$V+ + 0.3$	V
		Receivers	± 30	
V_O	Output voltage range	Drivers	$V- - 0.3$	V
		Receivers	$V_{CC} + 0.3$	
	Short-circuit duration	DOUT		Continuous
θ_{JA}	Package thermal impedance ⁽³⁾⁽⁴⁾	DB package		62
		DW package		46
T_J	Operating virtual junction temperature			150
T_{stg}	Storage temperature range	-65	150	$^{\circ}\text{C}$

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to network GND.
- (3) Maximum power dissipation is a function of $T_J(\text{max})$, θ_{JA} , and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(\text{max}) - T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability.
- (4) The package thermal impedance is calculated in accordance with JESD 51-7.

Recommended Operating Conditions⁽¹⁾

See [Figure 6](#)

		MIN	NOM	MAX	UNIT
Supply voltage		4.5	5	5.5	V
V_{IH}	Driver high-level input voltage	DIN			V
	Control high-level input voltage	$\overline{\text{EN}}$, SHDN			
V_{IL}	Driver and control low-level input voltage	DIN, $\overline{\text{EN}}$, SHDN			0.8
V_I	Driver and control input voltage	DIN, $\overline{\text{EN}}$, SHDN			5.5
	Receiver input voltage	-30	30		V
T_A	Operating free-air temperature	TRS211C			70
		TRS211I			85

- (1) Test conditions are C1–C4 = 0.1 μF at $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$.

Electrical Characteristics⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
I_{CC}	Supply current	No load,	See Figure 6	14	20
	Shutdown supply current	$T_A = 25^{\circ}\text{C}$,	See Figure 1	1	10

- (1) Test conditions are C1–C4 = 0.1 μF at $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$.
- (2) All typical values are at $V_{CC} = 5 \text{ V}$, and $T_A = 25^{\circ}\text{C}$.

DRIVER SECTION

Electrical Characteristics⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see [Figure 4](#))

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
V _{OH}	High-level output voltage	All DOUT at R _L = 3 k Ω to GND	5	9		V
V _{OL}	Low-level output voltage	All DOUT at R _L = 3 k Ω to GND	–5	–9		V
I _{IH}	Driver high-level input current	DIN = V _{CC}		15	200	μ A
	Control high-level input current	$\overline{\text{EN}}$, SHDN = V _{CC}		3	10	
I _{IL}	Driver low-level input current	DIN = 0 V		–15	–200	μ A
	Control low-level input current	$\overline{\text{EN}}$, SHDN = 0 V		–3	–10	
I _{OS}	Short-circuit output current ⁽³⁾	V _{CC} = 5.5 V, V _O = 0 V		± 10	± 60	mA
r _o	Output resistance	V _{CC} , V+, and V– = 0 V, V _O = ± 2 V	300			Ω

(1) Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 5 V \pm 0.5 V.

(2) All typical values are at V_{CC} = 5 V, and T_A = 25°C.

(3) Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

Switching Characteristics⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
	Maximum data rate	C _L = 50 pF to 1000 pF, R _L = 3 k Ω to 7 k Ω , One DOUT switching, See Figure 2	120			kbit/s
t _{PLH(D)}	Propagation delay time, low- to high-level output	C _L = 2500 pF, R _L = 3 k Ω , All drivers loaded, See Figure 2		2		μ s
t _{PHL(D)}	Propagation delay time, high- to low-level output	C _L = 2500 pF, R _L = 3 k Ω , All drivers loaded, See Figure 2		2		μ s
t _{sk(p)}	Pulse skew ⁽³⁾	C _L = 150 pF to 2500 pF, R _L = 3 k Ω to 7 k Ω , See Figure 3		300		ns
SR(tr)	Slew rate, transition region	C _L = 50 pF to 1000 pF, R _L = 3 k Ω to 7 k Ω , V _{CC} = 5 V	3	6	30	V/ μ s

(1) Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 5 V \pm 0.5 V.

(2) All typical values are at V_{CC} = 5 V, and T_A = 25°C.

(3) Pulse skew is defined as |t_{PLH} – t_{PHL}| of each channel of the same device.

ESD Protection

PIN	TEST CONDITIONS	TYP	UNIT
DOUT, RIN	Human-Body Model	± 15	kV

TRS211
5-V MULTICHANNEL RS-232 LINE DRIVER/RECEIVER
WITH ±15-kV ESD PROTECTION

SLLS811–JULY 2007

RECEIVER SECTION

Electrical Characteristics⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see [Figure 6](#))

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
V _{OH}	High-level output voltage	I _{OH} = -1 mA	3.5	V _{CC} - 0.4		V
V _{OL}	Low-level output voltage	I _{OH} = 1.6 mA			0.4	V
V _{IT+}	Positive-going input threshold voltage	V _{CC} = 5 V, T _A = 25°C		1.7	2.4	V
V _{IT-}	Negative-going input threshold voltage	V _{CC} = 5 V, T _A = 25°C	0.8	1.2		V
V _{hys}	Input hysteresis (V _{IT+} - V _{IT-})		0.2	0.5	1	V
r _i	Input resistance	V _{CC} = 5 V, T _A = 25°C	3	5	7	kΩ
	Output leakage current	$\overline{EN} = V_{CC}$, 0 ≤ R _{OUT} ≤ V _{CC}		±0.05	±10	µa

(1) Test conditions are C1–C4 = 0.1 µF at V_{CC} = 5 V ± 0.5 V.

(2) All typical values are at V_{CC} = 5 V, and T_A = 25°C.

Switching Characteristics⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽²⁾	MAX	UNIT
t _{PLH(R)}	Propagation delay time, low- to high-level output	C _L = 150 pF, See Figure 4		0.5	10	µs
t _{PHL(R)}	Propagation delay time, high- to low-level output	C _L = 150 pF, See Figure 4		0.5	10	µs
t _{en}	Output enable time	C _L = 150 pF, R _L = 1 kΩ, See Figure 5		600		ns
t _{dis}	Output disable time	C _L = 150 pF, R _L = 1 kΩ, See Figure 5		200		ns
t _{sk(p)}	Pulse skew ⁽³⁾	See Figure 3		300		ns

(1) Test conditions are C1–C4 = 0.1 µF at V_{CC} = 5 V ± 0.5 V.

(2) All typical values are at V_{CC} = 5 V, and T_A = 25°C.

(3) Pulse skew is defined as |t_{PLH} - t_{PHL}| of each channel of the same device.

PARAMETER MEASUREMENT INFORMATION

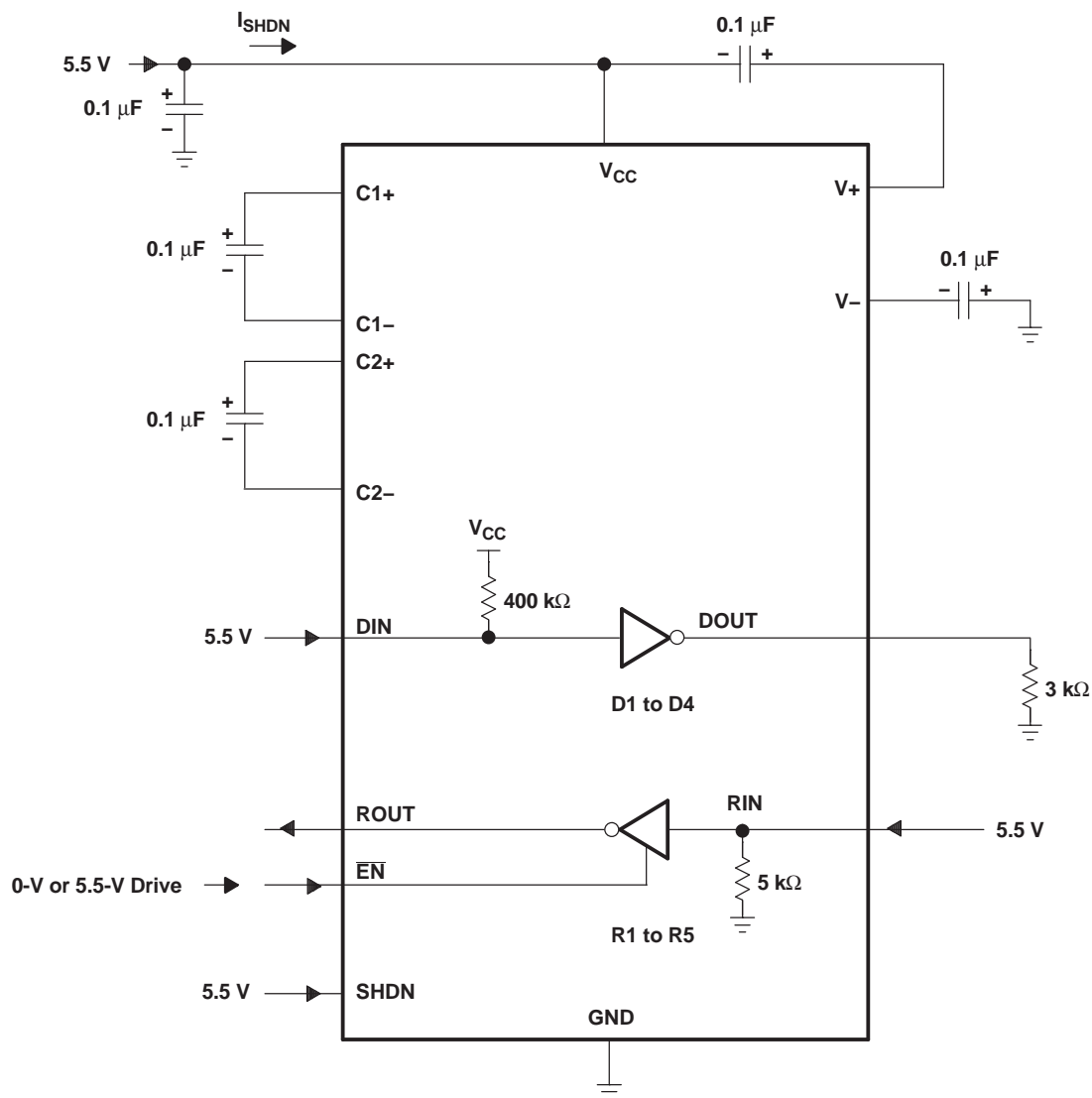
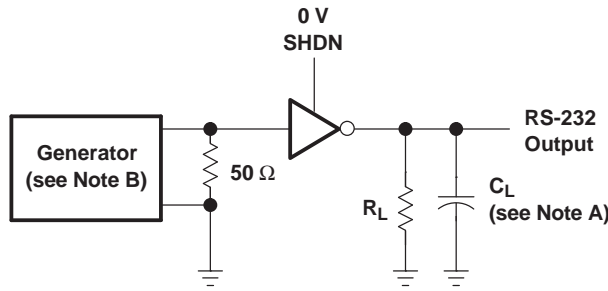
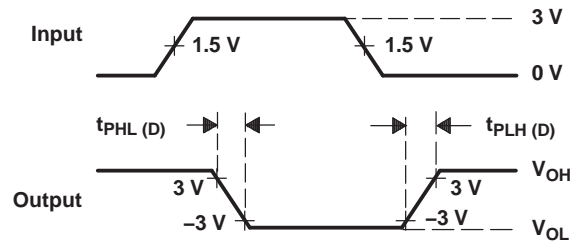


Figure 1. Shutdown Current Test Circuit

PARAMETER MEASUREMENT INFORMATION (continued)



TEST CIRCUIT

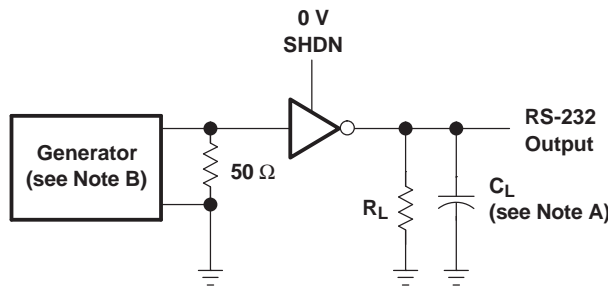


VOLTAGE WAVEFORMS

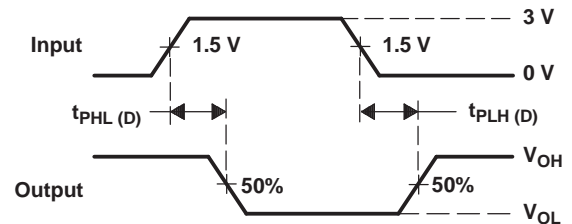
$$SR(tr) = \frac{6\text{ V}}{t_{PHL(D)} \text{ or } t_{PLH(D)}}$$

- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 120 kbit/s, $Z_O = 50\ \Omega$, 50% duty cycle, $t_r \leq 10\text{ ns}$, $t_f \leq 10\text{ ns}$.

Figure 2. Driver Slew Rate and Propagation Delay Times



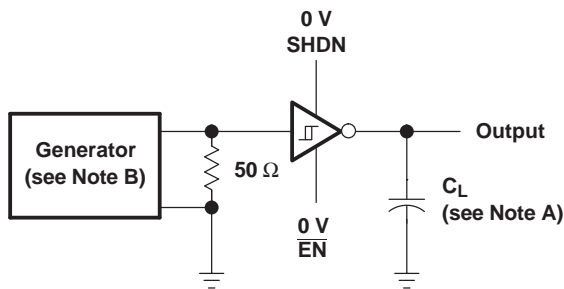
TEST CIRCUIT



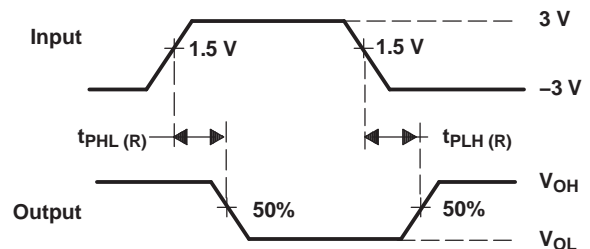
VOLTAGE WAVEFORMS

- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 120 kbit/s, $Z_O = 50\ \Omega$, 50% duty cycle, $t_r \leq 10\text{ ns}$, $t_f \leq 10\text{ ns}$.

Figure 3. Driver Pulse Skew



TEST CIRCUIT

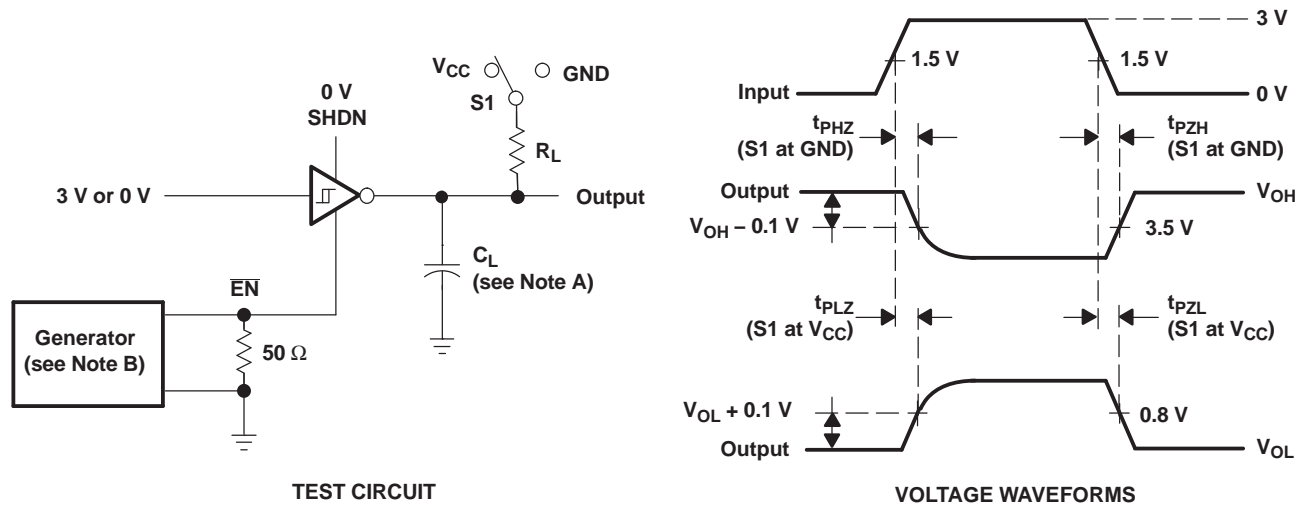


VOLTAGE WAVEFORMS

- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: $Z_O = 50\ \Omega$, 50% duty cycle, $t_r \leq 10\text{ ns}$, $t_f \leq 10\text{ ns}$.

Figure 4. Receiver Propagation Delay Times

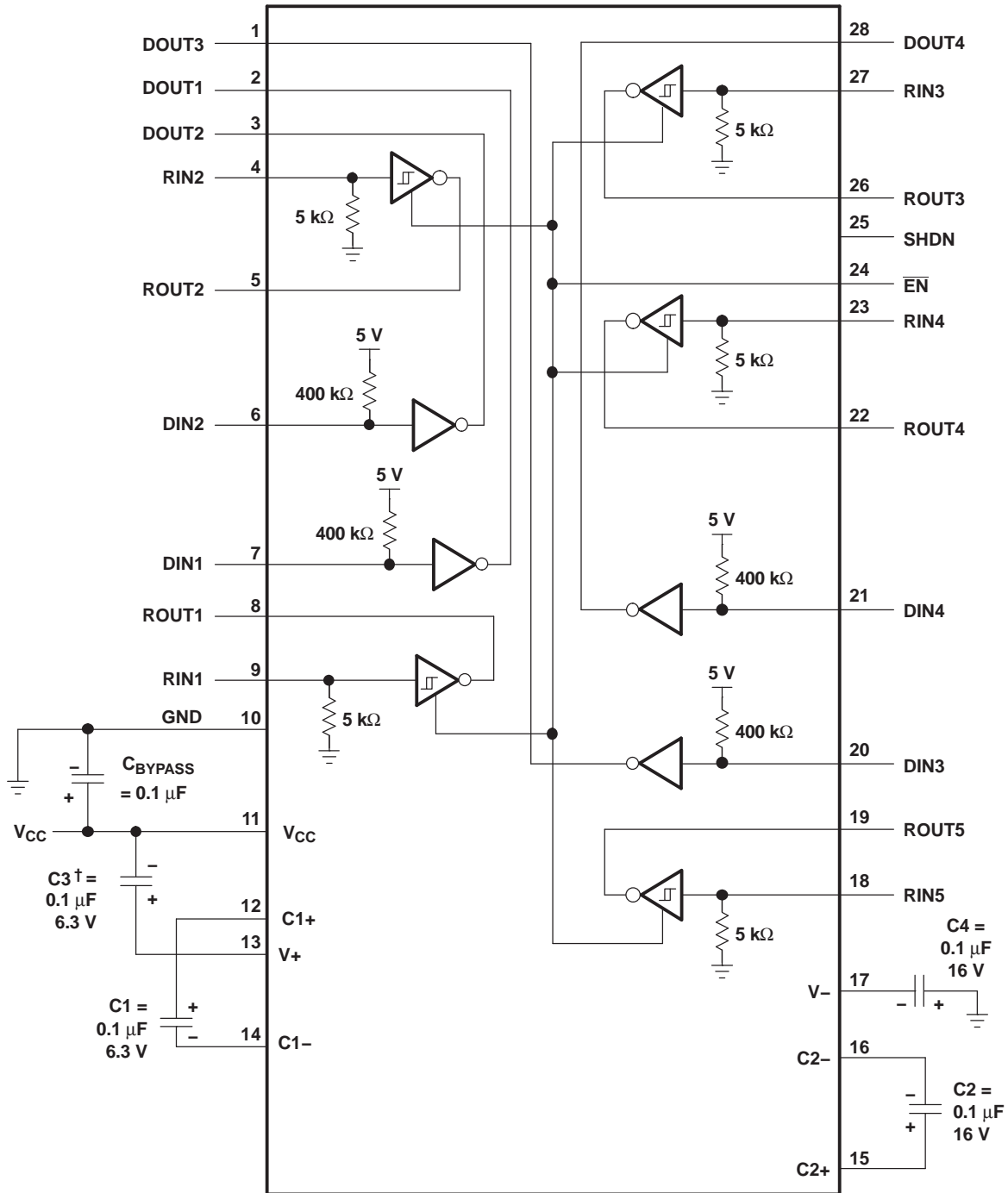
PARAMETER MEASUREMENT INFORMATION (continued)



- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, 50% duty cycle, $t_r \leq 10$ ns, $t_f \leq 10$ ns.
- C. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- D. t_{PZL} and t_{PZH} are the same as t_{en} .

Figure 5. Receiver Enable and Disable Times

APPLICATION INFORMATION



† C3 can be connected to V_{CC} or GND.

- A. Resistor values shown are nominal.
- B. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

Figure 6. Typical Operating Circuit and Capacitor Values

APPLICATION INFORMATION (continued)

Capacitor Selection

The capacitor type used for C1–C4 is not critical for proper operation. The TRS211 requires 0.1- μ F capacitors, although capacitors up to 10 μ F can be used without harm. Ceramic dielectrics are suggested for the 0.1- μ F capacitors. When using the minimum recommended capacitor values, make sure the capacitance value does not degrade excessively as the operating temperature varies. If in doubt, use capacitors with a larger (e.g., 2 \times) nominal value. The capacitors' effective series resistance (ESR), which usually rises at low temperatures, influences the amount of ripple on V+ and V–.

Use larger capacitors (up to 10 μ F) to reduce the output impedance at V+ and V–.

Bypass V_{CC} to ground with at least 0.1 μ F. In applications sensitive to power-supply noise generated by the charge pumps, decouple V_{CC} to ground with a capacitor the same size as (or larger than) the charge-pump capacitors (C1–C4).

Electrostatic Discharge (ESD) Protection

TI TRS211 devices have standard ESD protection structures incorporated on the pins to protect against electrostatic discharges encountered during assembly and handling. In addition, the RS232 bus pins (driver outputs and receiver inputs) of these devices have an extra level of ESD protection. Advanced ESD structures were designed to successfully protect these bus pins against ESD discharge of ± 15 kV when powered down.

ESD Test Conditions

ESD testing is stringently performed by TI, based on various conditions and procedures. Please contact TI for a reliability report that documents test setup, methodology, and results.

Human-Body Model (HBM)

The HBM of ESD testing is shown in [Figure 7](#). [Figure 8](#) shows the current waveform that is generated during a discharge into a low impedance. The model consists of a 100-pF capacitor charged to the ESD voltage of concern and subsequently discharged into the DUT through a 1.5-k Ω resistor.

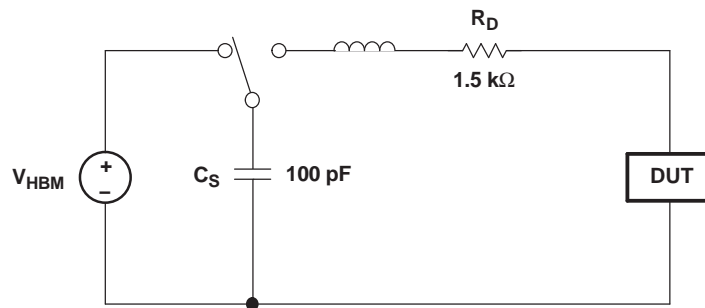


Figure 7. HBM ESD Test Circuit

APPLICATION INFORMATION (continued)

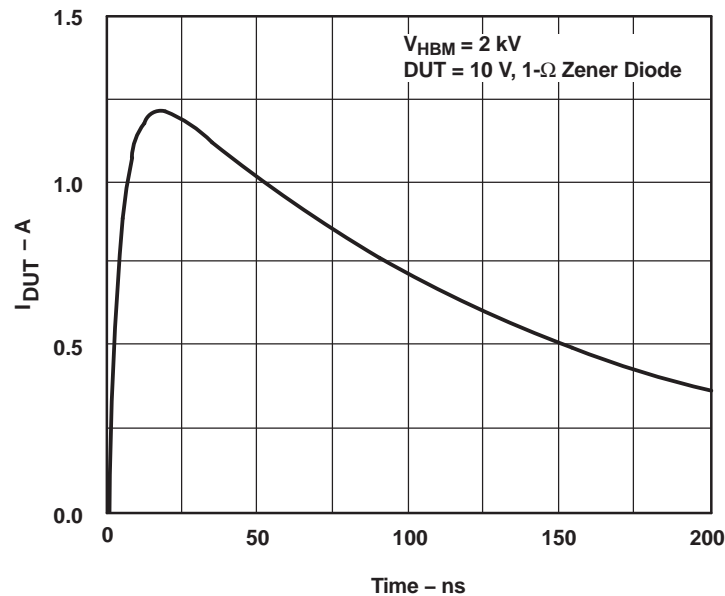


Figure 8. Typical HBM Current Waveform

Machine Model (MM)

The MM ESD test applies to all pins, using a 200-pF capacitor with no discharge resistance. The purpose of the MM test is to simulate possible ESD conditions that can occur during the handling and assembly processes of manufacturing. In this case, ESD protection is required for all pins, not just RS-232 pins. However, after PC board assembly, the MM test no longer is as pertinent to the RS-232 pins.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TRS211CDB	ACTIVE	SSOP	DB	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	TRS211C	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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DB (R-PDSO-G**)

PLASTIC SMALL-OUTLINE

28 PINS SHOWN



- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
 D. Falls within JEDEC MO-150

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